

MX8290

82V N-channel enhancement mode MOSFET

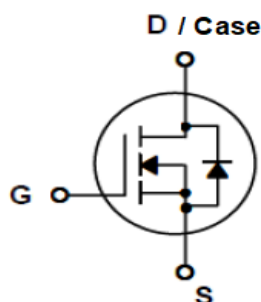
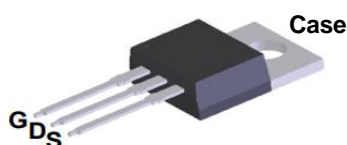
Features

- Extremely Low RDS(on):
Typ.RDS(on) = 6.5mΩ @ $V_{GS}=10\text{ V}$, $I_D=40\text{ A}$
- Low gate charge (typical 106 nC)
- Fast switching
- 100% avalanche tested

General Description

The MX8290 uses advanced trench technology to provide excellent RDS(ON), low gate charge and operation with gate voltages as low as 3V. This device is suitable for use as a Battery protection or in other Switching application.

TO-220-3L Package



Symbol	Parameter	Value	Units
V_{DS}	Drain-Source Voltage	82	V
I_D	Drain Current - Continuous (TC= 25°C) - Continuous (TC= 100°C)	90	A
		70*	A
I_{DM}	Drain Current - Pulsed (Note 1)	320*	A
V_{GS}	Gate-Source Voltage	± 20	V
E_{AS}	Single Pulsed Avalanche Energy (Note 2)	602	mJ
E_{AR}	Repetive Avalanche Energy (Note 1)	50	mJ
dv/dt	Peak diode recovery dv/dt (note 3)	5	V/ns
P_D	Power Dissipation (TC = 25°C) - Derate above 25°C	255	W
		2.0	W/°C
T_j, T_{stg}	Operating and Storage Temperature Range	-55 to +150	°C
T_L	Maximum lead temperature for soldering purpose, 1/8 from case for 5 seconds	300	°C

* Drain current limited by maximum junction temperature

Thermal Characteristics

Symbol	Parameter	Value	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.49	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	57.6	°C/W

Electrical Characteristics TC = 25°C unless otherwise noted						
Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Off Characteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250 μA	82	88		V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		75.8		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 802V, V _{GS} = 0 V			1	μA
		V _{DS} = 64 V, T _C = 125°C			10	μA
I _{GSSF}	Gate Leakage Current, Forward	V _{GS} = 20 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate Leakage Current, Reverse	V _{GS} = -20 V, V _{DS} = 0 V			-100	nA
On Characteristics						
V _{GS(TH)}	Gate Threshold voltage	V _{DS} = V _{GS} , I _D = 250 uA	2	3	4	V
R _{DS(On)}	Drain-Source on-state resistance	V _{GS} = 10 V, I _D = 40 A		6.5	7.5	mΩ
g _{FS}	Forward Transconductance	V _{DS} = 10 V, I _D = 40 A (Note 3)		37.5		S
Dynamic Characteristics						
C _{iss}	Input capacitance	V _{DS} = 25 V, V _{GS} = 0 V, f = 1.0 MHz		6700		pF
C _{oss}	Output capacitance			381		pF
C _{rss}	Reverse transfer capacitance			284		pF
Switching Characteristics						
t _{d(on)}	Turn On Delay Time	V _{DD} = 40 V, ID = 40 A, V _{GS} = 10 V, R _G = 4.7 Ω (Note 3, 4)		28		ns
t _r	Rising Time			55		ns
t _{d(off)}	Turn Off Delay Time			69		ns
t _f	Fall Time			27		ns
Q _g	Total Gate Charge	V _{DS} = 40 V, ID = 40 A, V _{GS} = 10 V (Note 3, 4)		106		nC
Q _{gs}	Gate-Source Charge			35		nC
Q _{gd}	Gate-Drain Charge			25.5		nC
R _g	Gate Resistance	V _{DS} = 0 V, Scan F mode		0.74		Ω
Drain-Source Diode Characteristics and Maximum Ratings						
I _S	Maximum Continuous Drain-Source Diode Forward Current				90	A
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				320	A
V _{SD}	Diode Forward Voltage	V _{GS} = 0 V, I _S = 40 A			1.2	V
I _{rrm}	Reverse recovery current	I _S = 40A, V _{GS} = 0V, di _F /dt = 100A/us		-2.8		A
T _{rr}	Reverse recovery time			37		ns
Q _{rr}	Reverse recovery charge			52		nC
Notes: 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 1.54 mH, IAS = 28 A, VDD = 10V, RG = 25 Ω, Starting Tj = 25°C 3. ISD ≤ 40A, di/dt = 100A/us, VDD ≤ BVDS, Starting Tj =25°C 4. Pulse Test : Pulse width ≤ 300us, Duty cycle ≤ 2% 5. Essentially independent of operating temperature						

Typical Characteristics

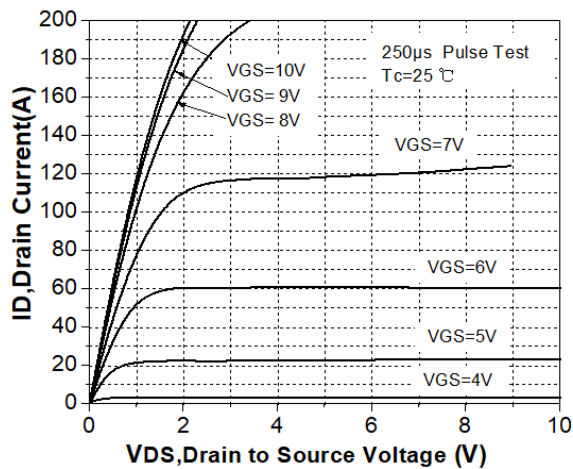


Figure 1. On-Region Characteristics

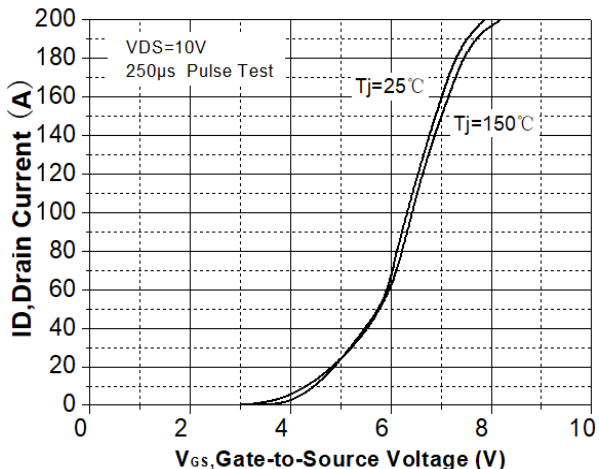


Figure 2. Transfer Characteristics

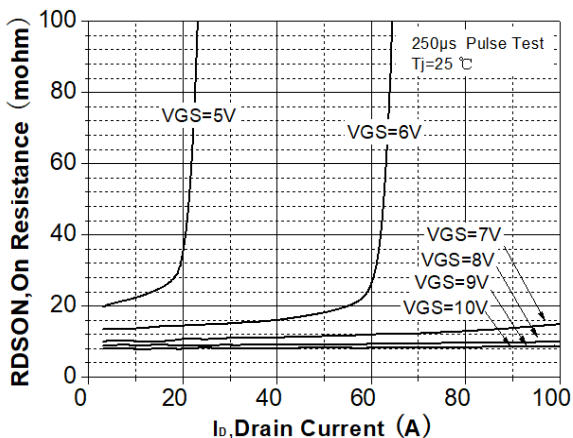


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

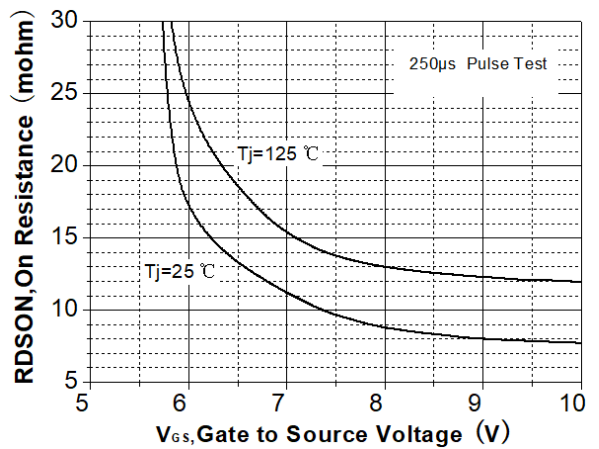


Figure 4. On-Resistance vs. Gate to Source Voltage

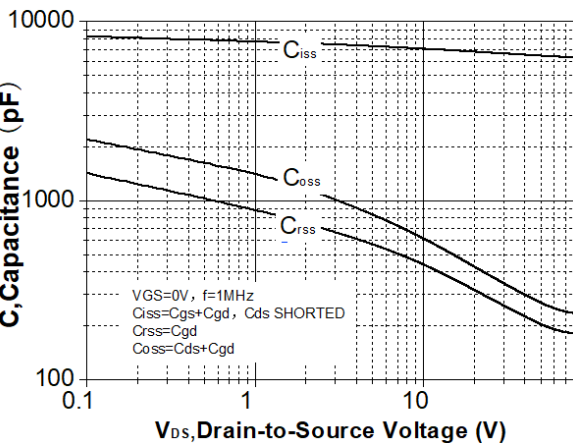


Figure 5. Capacitance Characteristics

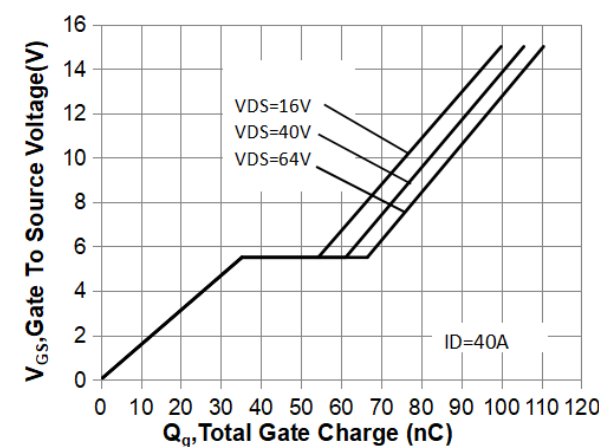


Figure 6. Gate Charge Characteristics

Typical Characteristics (Continued)

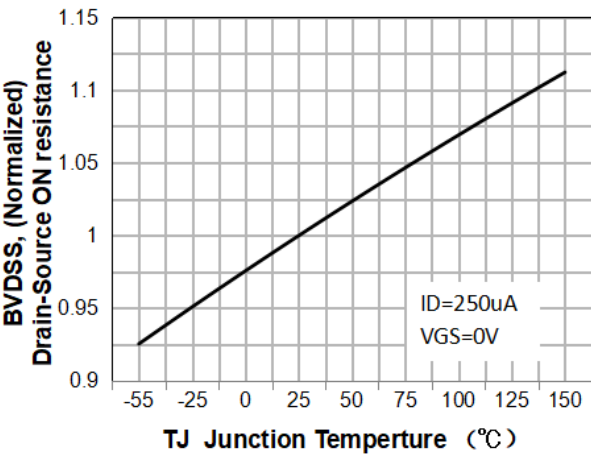


Figure 7. Breakdown Voltage Variation vs Temperature

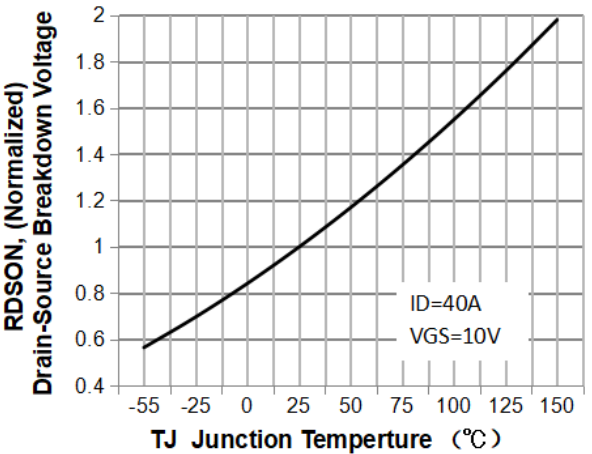


Figure 8. On-Resistance Variation vs Temperature

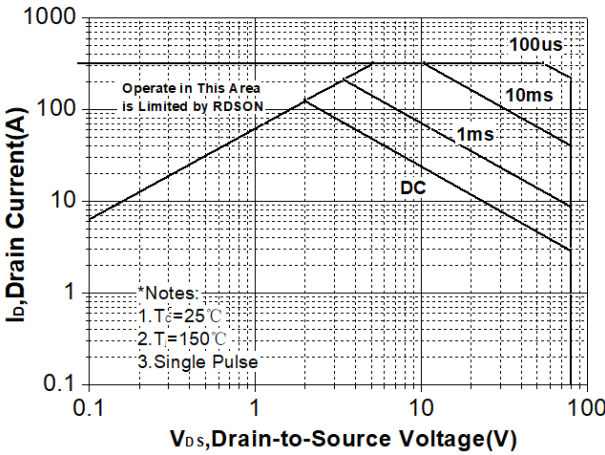


Figure 9. Maximum Safe Operating Area

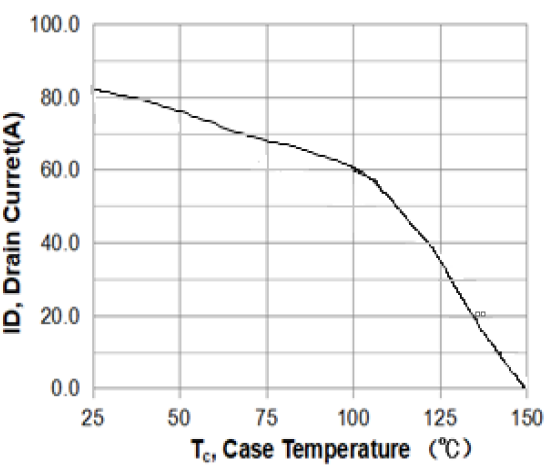


Figure 10. Maximum Drain Current vs Case Temperature

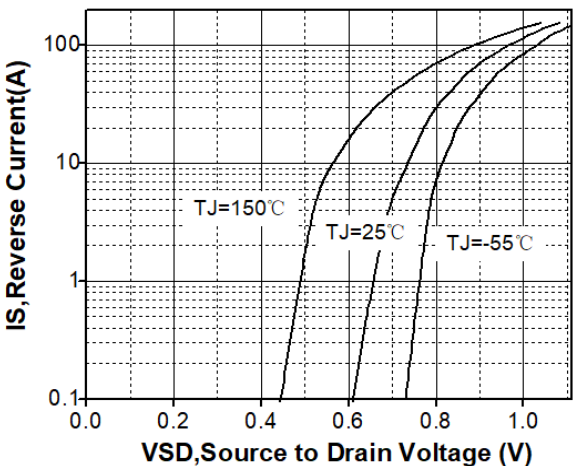


Figure 11. Body Diode Forward Voltage Vs Reverse Drain Current

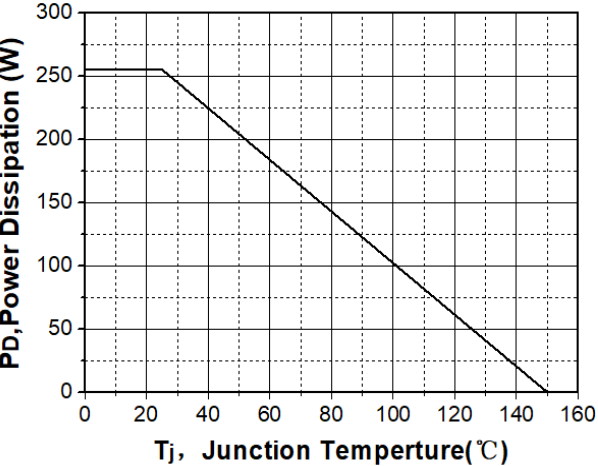


Figure 12. Power Dissipation vs Junction Temperature

Typical Characteristics (Continued)

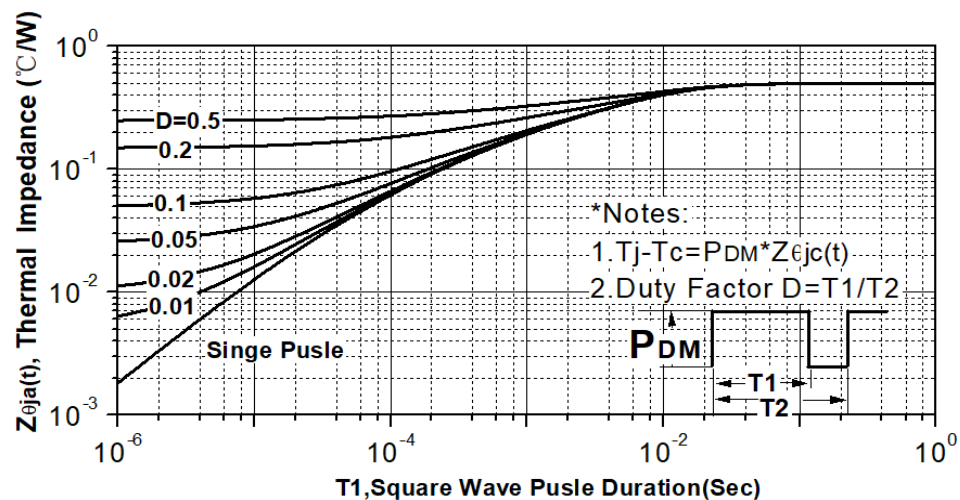


Figure 13. Transient Thermal Response Curve

Test Circurt&Waveform

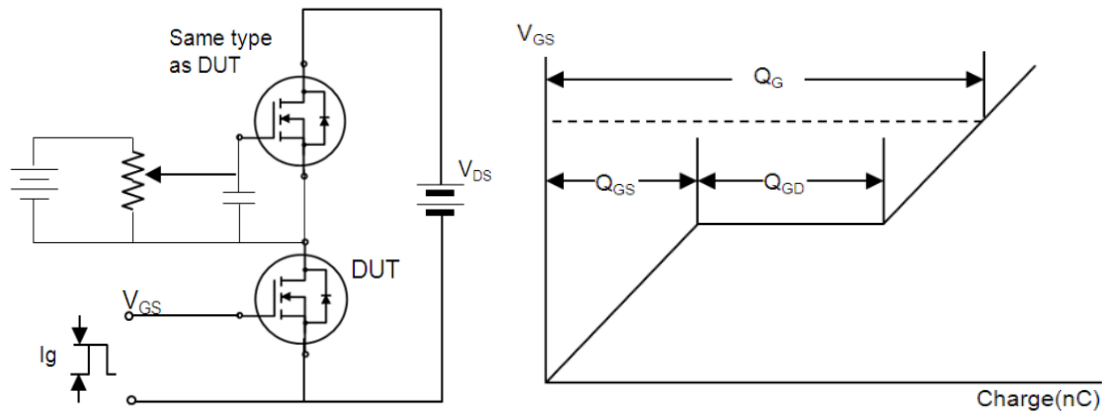


Figure 14. Gate charge test circuit & waveform

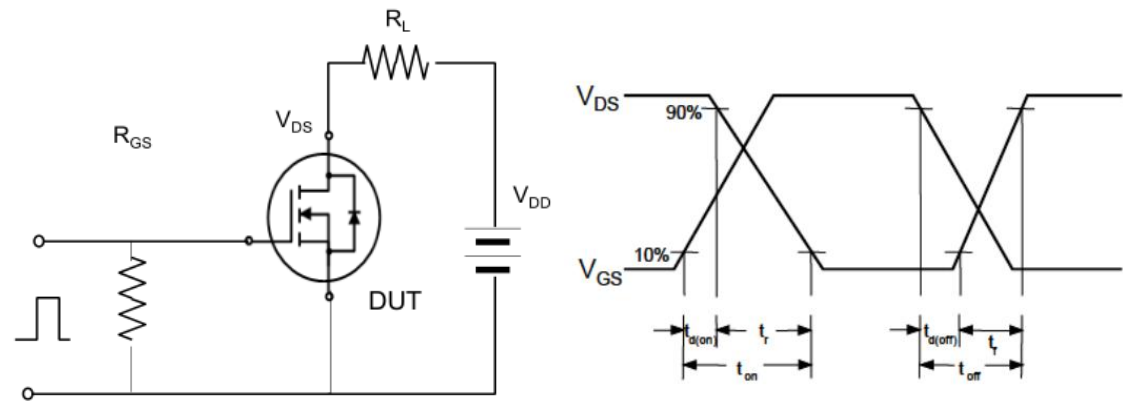


Figure 15. Switching time test circuit & waveform

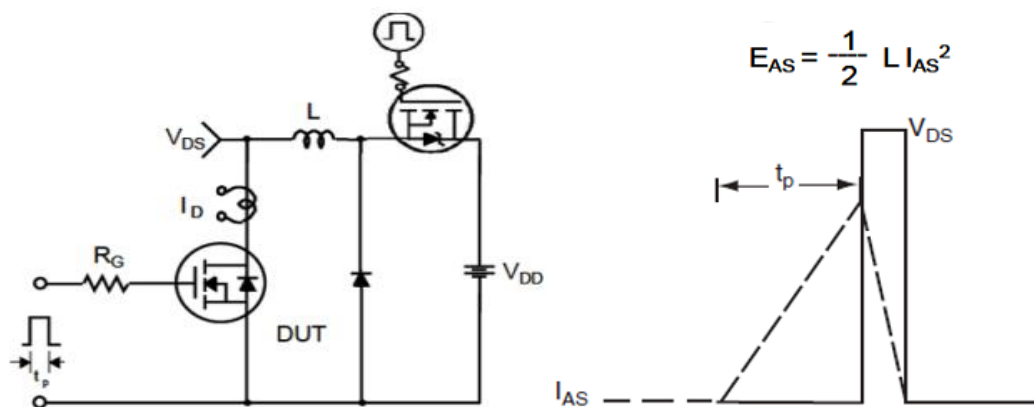


Figure 16. Unclamped Inductive switching test circuit & waveform

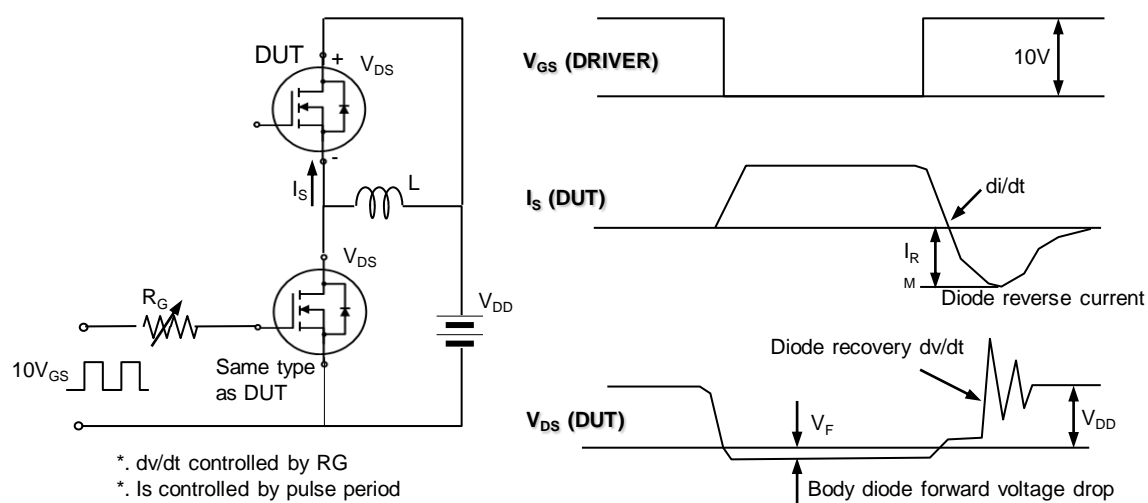
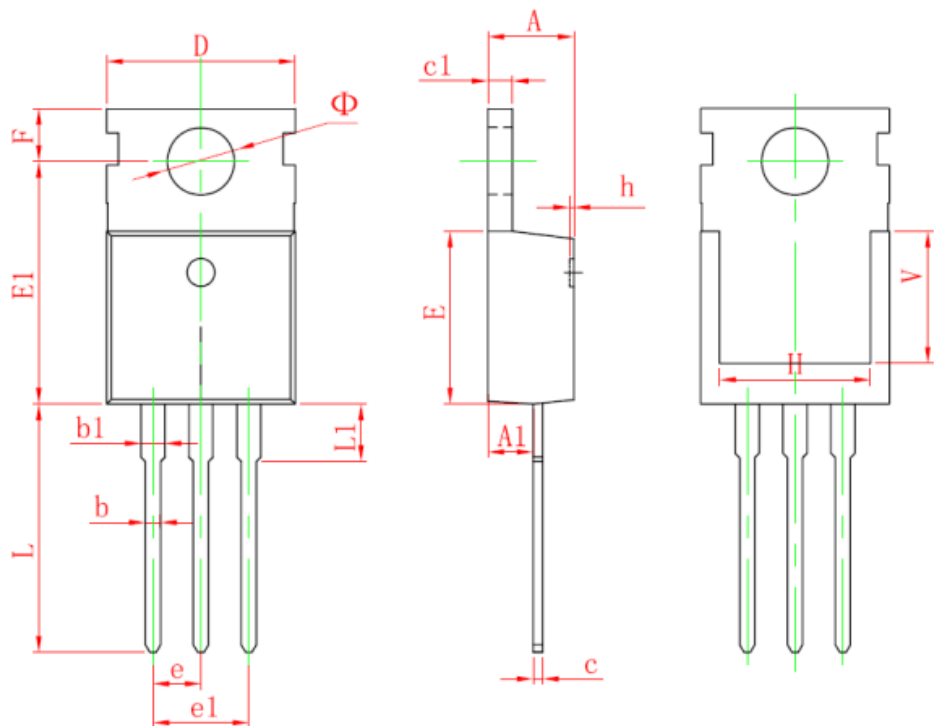


Figure 17. Peak diode recovery dv/dt test circuit & waveform

Package Dimensions : TO-220-3L(T0.5mm) PACKAGE



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	4.400	4.600	0.173	0.181
A1	2.250	2.550	0.089	0.100
b	0.710	0.910	0.028	0.036
b1	1.170	1.370	0.046	0.054
c	0.330	0.650	0.013	0.026
c1	1.200	1.400	0.047	0.055
D	9.910	10.250	0.390	0.404
E	8.950	9.750	0.352	0.384
E1	12.650	13.050	0.498	0.514
e	2.540 TYP.		0.100 TYP.	
e1	4.980	5.180	0.196	0.204
F	2.650	2.950	0.104	0.116
H	7.900	8.100	0.311	0.319
h	0.000	0.300	0.000	0.012
L	12.900	13.400	0.508	0.528
L1	2.850	3.250	0.112	0.128
V	6.900 REF.		0.276 REF.	
Φ	3.400	3.800	0.134	0.150